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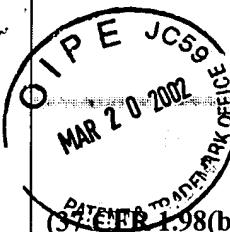
Hans Tandler et al.

FILING DATE

April 12, 2000

GROUP

2872



INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS

Examiner Initial	Cite No. <sup>1</sup>	Patent Number	Issue Date	Patentee	Class/ Subclass	Filing Date
gw		5,187,702	February 16, 1993	Naomasa Takahashi		December 27, 1990
gw		5,365,296	November 15, 1994	Junichi Murakami et al.		October 29, 1991
gw		5,563,853	October 8, 1996	Kazuyoshi Ishii		November 2, 1995
gw		5,612,740	March 18, 1997	Chung-Shing Lee et al.		August 16, 1995
gw		5,623,372	April 22, 1997	Tsutomu Matsui		June 14, 1995

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

Examiner Initial	Document Number	Publication Date	Country or Patent Office	Class/ Subclass	Translation Yes/No
gw	DE 26 11 639	9/22/77	GERMANY		*No
gw	DE 43 15 630	10/11/94	GERMANY		*No
gw	DE 29 602202	8/29/96	GERMANY		*No
gw	DE 38 08 510	2/2/89	GERMANY		*No
gw	DE 42 24 824	1/28/93	GERMANY		*No
gw	EP 646 769	4/5/95	EUROPE		*No
gw	EP 744 650	11/27/96	EUROPE		*No

OTHER DOCUMENTS  
(Including Author, Title, Date, Relevant Pages, Place of Publication)

Examiner Initial	Cite No. <sup>1</sup>	
gw		*English Abstract of DE 26 11 639
gw		*English Abstract of DE 43 15 630
gw		*English Abstract of DE 29 602202
gw		*English Abstract of DE 38 08 510
gw		*English Abstract of DE 42 24 824
gw		*English Abstract of EP 646 769
gw		*English Abstract of EP 744 650
gw		Knaurs Lexikon der Technik 1988, p. 59 with English Abstract

EXAMINER	DATE CONSIDERED
Winstedt, J. <i>Jennifer Winstedt</i>	5/29/02

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.